

Quadruple 2-Input Exclusive OR Gates

UT54ACTS86/UT54ACS86

Features

- 1.2 μ CMOS (ACTS) and 0.6 μ CRH CMOS (ACS)
 - Latchup immune
- High speed
- Low power consumption
- Single 5 volt supply
- Available QML Q or V processes
- Flexible package
 - 14-pin DIP (ACTS only)
 - 14-lead flatpack
- UT54ACS86 - SMD 5962-96538
- UT54ACTS86 - SMD 5962-96539

Description

The UT54ACS86 and the UT54ACTS86 are quadruple 2-input exclusive OR gates. The devices perform the Boolean function $Y = A \oplus B = \bar{A}B + A\bar{B}$ in positive logic.

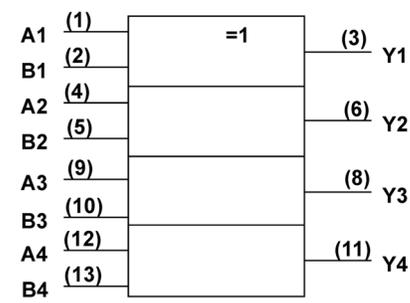
An application is as a true/complement element. If one of the inputs is low, the other input will be reproduced in true form at the output. If one of the inputs is high, the signal on the other input will be reproduced inverted at the output.

The devices are characterized over full military temperature range of -55°C to +125°C.

Function Table

Inputs		Output
A	B	Y
L	L	L
L	H	H
H	L	H
H	H	L

Logic Symbol

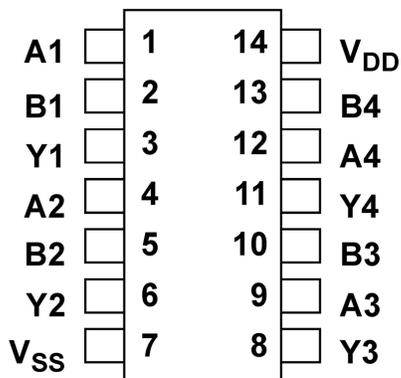


Note:

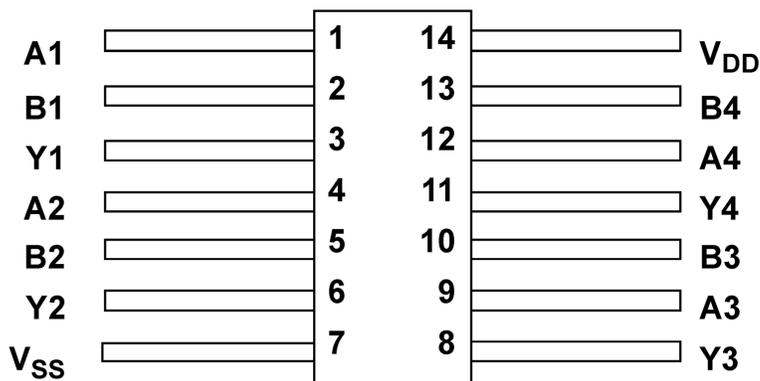
- 1) Logic symbol in accordance with ANSI/IEEE standard 91-1984 and IEC Publication 617.12

UT54ACTS86/UT54ACS86

Pinouts

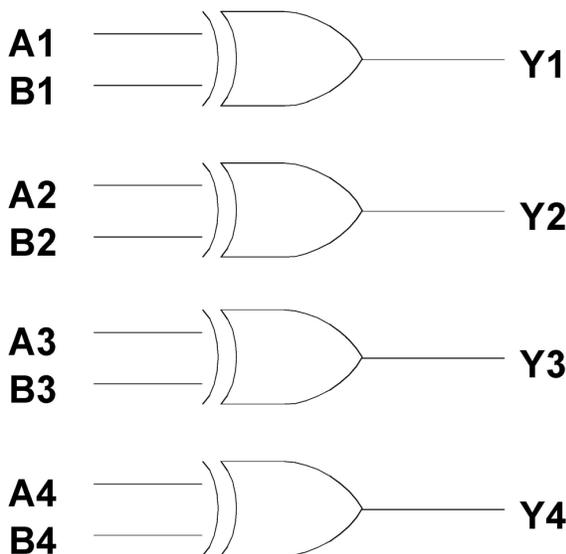


14-Pin Dip Top View



14-Lead Flatpack Top View

Logic Diagram



Quadruple 2-Input Exclusive OR Gates

UT54ACTS86/UT54ACS86

Operational Environment ¹

Parameter	Limit	Units
Total Dose	1.0E6 (ACTS) 500K (ACS)	rads(Si)
SEU Threshold ²	80	MeV-cm ² /mg
SEL Threshold	120	MeV-cm ² /mg
Neutron Fluence	1.0E14	n/cm ²

Notes:

- 1) Logic will not latchup during radiation exposure within the limits defined in the table.
- 2) Device storage elements are immune to SEU affects.

Absolute Maximum Ratings

Symbol	Parameter	Limit	Units
V _{DD}	Supply voltage	-0.3 to 7.0	V
V _{I/O}	Voltage any pin	-.3 to V _{DD} +.3	V
T _{STG}	Storage Temperature range	-65 to +150	°C
T _J	Maximum junction temperature	+175	°C
T _{LS}	Lead temperature (soldering 5 seconds)	+300	°C
Θ _{JC}	Thermal resistance junction to case	15	°C/W
I _I	DC input current	±10	mA
P _D	Maximum power dissipation	1	W

Notes:

- 1) Stresses outside the listed absolute maximum ratings may cause permanent damage to the device. This is a stress rating only, functional operation of the device at these or any other condition beyond limits indicated in the operational sections is not recommended. Exposure to absolute maximum rating conditions for extended periods may affect device reliability.

Recommended Operating Conditions

Symbol	Parameter	Limit	Units
V _{DD}	Supply voltage	4.5 to 5.5	V
V _{IN}	Input voltage any pin	0 to V _{DD}	V
T _C	Temperature range	-55 to + 125	°C

UT54ACTS86/UT54ACS86

DC Electrical Characteristics ⁷

($V_{DD} = 5.0V \pm 10\%$; $V_{SS} = 0V$ ⁶, $-55^{\circ}C < T_c < +125^{\circ}C$); Unless otherwise noted, T_c is per the temperature range ordered.

Symbol	Parameter	Condition	MIN	MAX	Unit
V_{IL}	Low-level input voltage ¹ ACTS ACS			0.8 .3 V_{DD}	V
V_{IH}	High-level input voltage ¹ ACTS ACS		.5 V_{DD} .7 V_{DD}		V
I_{IN}	Input leakage current ACTS/ACS	$V_{IN} = V_{DD}$ or V_{SS}	-1	1	μA
V_{OL}	Low-level output voltage ³ ACTS ACS	$I_{OL} = 8.0mA$ $I_{OL} = 100\mu A$		0.40 0.25	V
V_{OH}	High-level output voltage ³ ACTS ACS	$I_{OH} = -8.0mA$ $I_{OH} = -100\mu A$.7 V_{DD} $V_{DD} - 0.25$		V
I_{OS}	Short-circuit output current ^{2, 4} ACTS/ACS	$V_O = V_{DD}$ and V_{SS}	-200	200	mA
I_{OL}	Output current ¹⁰ (Sink)	$V_{IN} = V_{DD}$ or V_{SS} $V_{OL} = 0.4V$	8		mA
I_{OH}	Output current ¹⁰ (Source)	$V_{IN} = V_{DD}$ or V_{SS} $V_{OH} = V_{DD} - 0.4V$	-8		mA
P_{total}	Power dissipation ^{2, 8, 9}	$C_L = 50pF$		1.8	mW/ MHz
I_{DDQ}	Quiescent Supply Current	Pre-Rad		10	μA
		Post-Rad Device Type - 01	$V_{DD} = V_{DD} MAX$	50	
ΔI_{DDQ}	Quiescent Supply Current Delta ACTS	For input under test $V_{IN} = V_{DD} - 2.1V$ For all other inputs $V_{IN} = V_{DD}$ or V_{SS} $V_{DD} = 5.5V$		1.6	mA
C_{IN}	Input capacitance ⁵	$f = 1MHz @ 0V$		15	pF
C_{OUT}	Output capacitance ⁵	$f = 1MHz @ 0V$		15	pF

Quadruple 2-Input Exclusive OR Gates

UT54ACTS86/UT54ACS86

Notes:

- 1) Functional tests are conducted in accordance with MIL-STD-883 with the following input test conditions: $V_{IH} = V_{IH(min)} + 20\%$, $- 0\%$; $V_{IL} = V_{IL(max)} + 0\%$, $- 50\%$, as specified herein, for TTL, CMOS, or Schmitt compatible inputs. Devices may be tested using any input voltage within the above specified range, but are guaranteed to $V_{IH(min)}$ and $V_{IL(max)}$.
- 2) Supplied as a design limit but not guaranteed or tested.
- 3) Per MIL-PRF-38535, for current density $\leq 5.0E5$ amps/cm², the maximum product of load capacitance (per output buffer) times frequency should not exceed 3,765 pF/MHz.
- 4) Not more than one output may be shorted at a time for maximum duration of one second.
- 5) Capacitance measured for initial qualification and when design changes may affect the value. Capacitance is measured between the designated terminal and V_{SS} at frequency of 1MHz and a signal amplitude of 50mV rms maximum.
- 6) Maximum allowable relative shift equals 50mV.
- 7) Device type 01 is only offered with a TID tolerance guarantee of 1E6 rads(Si) (ACTS only), 1E5 rads(Si), 3E5 rads(Si), and 5E5 rads(Si), and is tested in accordance with MIL-STD-883 Test Method 1019 Condition A.
- 8) Power does not include power contribution of any TTL output sink current.
- 9) Power dissipation specified per switching output.
- 10) This value is guaranteed based on characterization data, but not tested.

AC Electrical Characteristics ²

($V_{DD} = 5.0V \pm 10\%$; $V_{SS} = 0V$ ¹, $-55^{\circ}C < T_c < +125^{\circ}C$); Unless otherwise noted, T_c is per the temperature range ordered.

Symbol	Parameter	Minimum	Maximum	Unit
t_{PHL}	Data to input	1	14	ns
t_{PLH}	Data to input	1	13	ns

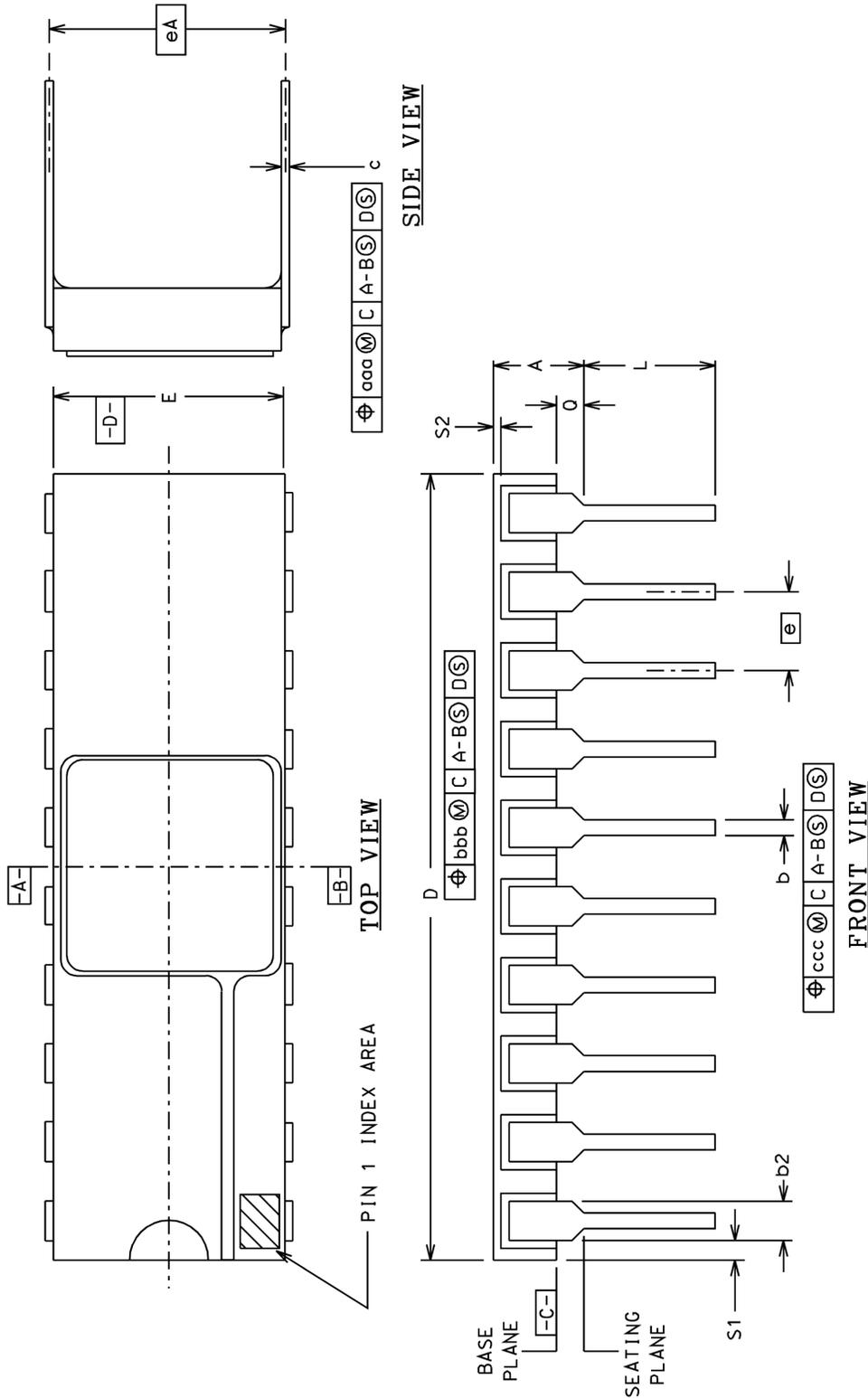
Notes:

- 1) Maximum allowable relative shift equals 50mV.
- 2) Device type 01 is only offered with a TID tolerance guarantee of 1E6 rads(Si) (ACTS only), 1E5 rads(Si), 3E5 rads(Si), and 5E5 rads(Si), and is tested in accordance with MIL-STD-883 Test Method 1019 Condition A.

Quadruple 2-Input Exclusive OR Gates

UT54ACTS86/UT54ACS86

Packaging Side-Braced Packages

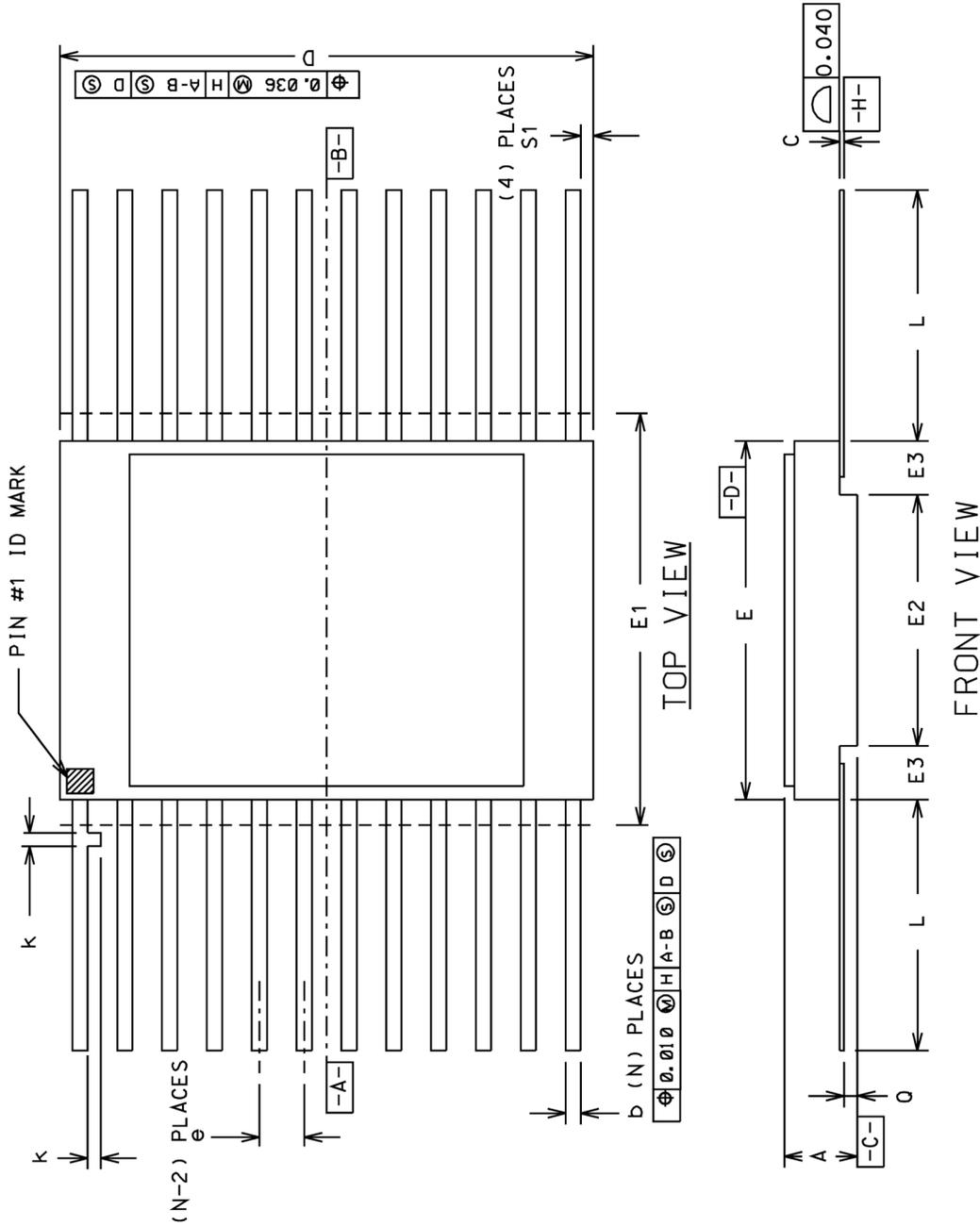


PKG CONF IG	LEAD COUNT	MIL-STD- 1835 DWG CONF C	DIMENSION SYMBOLS														
			A	b	b2	c	D	E	e	eA	L	Q	S1	S2	aaa	bbb	ccc
-01	14	D-1	0.200	0.026	0.065	0.018	0.785	0.310	0.100	0.300	0.200	0.060	---	---	0.015	0.030	0.010
			---	0.014	0.045	0.008	---	0.220	BSC	BSC	BSC	0.125	0.015	0.005	---	---	---
-02	16	D-2	0.200	0.026	0.065	0.018	0.840	0.310	0.100	0.300	0.200	0.060	---	---	0.015	0.030	0.010
			---	0.014	0.045	0.008	---	0.220	BSC	BSC	BSC	0.125	0.015	0.005	---	---	---
-03	20	D-8	0.200	0.026	0.065	0.018	1.060	0.310	0.100	0.300	0.200	0.070	---	---	0.015	0.030	0.010
			---	0.014	0.045	0.008	---	0.220	BSC	BSC	BSC	0.125	0.015	0.005	---	---	---

Quadruple 2-Input Exclusive OR Gates

UT54ACTS86/UT54ACS86

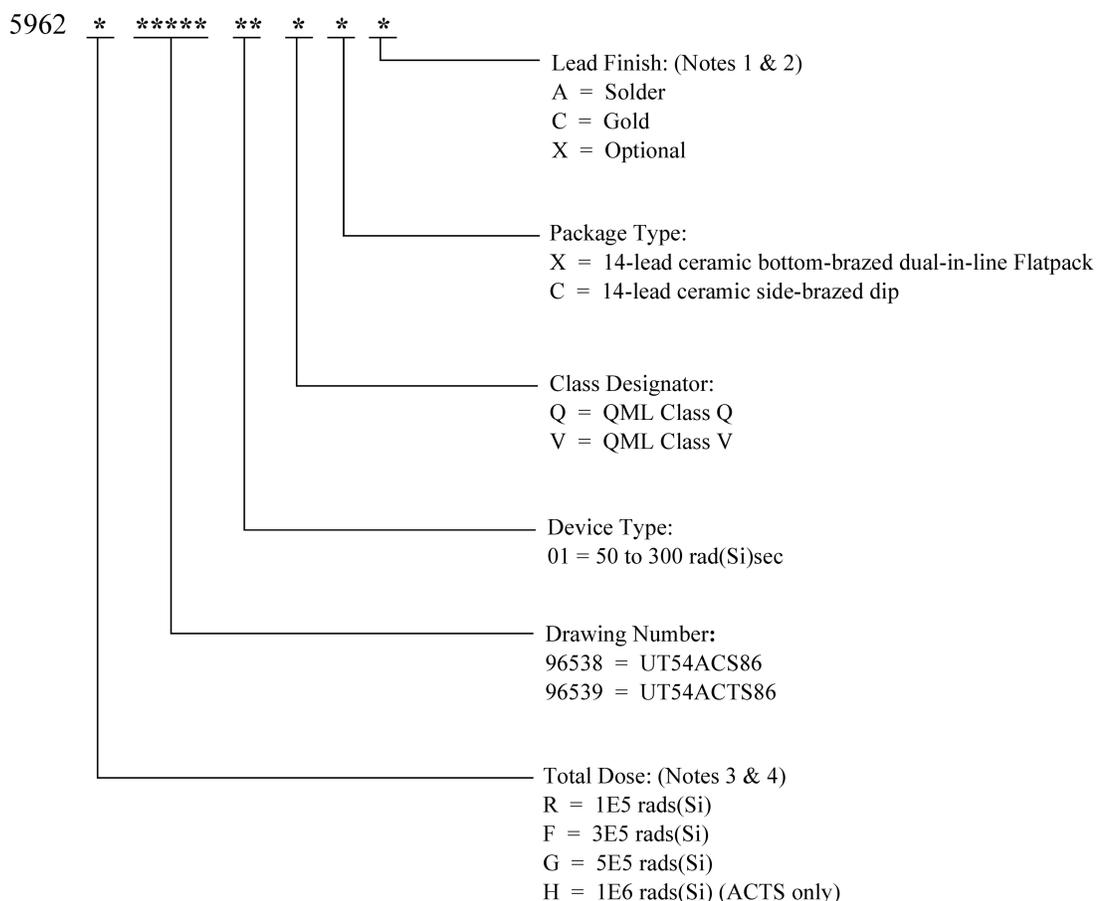
Flatpack Packages



PKG CONFIG	LEAD COUNT	MIL-STD 1835 DWG CONF B	DIMENSION SYMBOLS												
			A	b	c	D	E	E1	E2	E3	e	k	L	Q	S1
-03	14	F-2A	0.115 0.045	0.022 0.015	0.009 0.004	0.390 -----	0.260 0.235	0.290 -----	----- 0.130	----- 0.030	0.050 BSC	0.015 0.008	0.370 0.270	0.045 0.026	----- 0.005
-04	16	F-5A	0.115 0.045	0.022 0.015	0.009 0.004	0.440 -----	0.285 0.245	0.315 -----	----- 0.130	----- 0.030	0.050 BSC	0.015 0.008	0.370 0.250	0.045 0.026	----- 0.005
-05	20	F-9A	0.115 0.045	0.022 0.015	0.009 0.004	0.540 -----	0.300 0.245	0.330 -----	----- 0.130	----- 0.030	0.050 BSC	0.015 0.008	0.370 0.250	0.045 0.026	----- 0.000

UT54ACTS86/UT54ACS86

UT54ACS86/UT54ACTS86: SMD



Notes:

- 1) Lead finish (A, C, or X) must be specified.
- 2) If an "X" is specified when ordering, part marking will match the lead finish and will be either "A" (solder) or "C" (gold).
- 3) Total dose radiation must be specified when ordering. QML Q and QML V not available without radiation hardening. For prototype inquiries, contact factory.
- 4) Device type 01 is only offered with a TID tolerance guarantee of 1E6 rads(Si) (ACTS only), 1E5 rads(Si), 3E5 rads(Si), and 5E5 rads(Si), and is tested in accordance with MIL-STD-883 Test Method 1019 Condition A.

Datasheet Revision History

Revision Date	Description of Change	Author
10-17	Page 4 edited IDDQ Applied new CAES Data Sheet template to the document.	RT
1-18	Updated to reflect current SMD	RT

UT54ACTS86/UT54ACS86

Datasheet Definitions

	DEFINITION
Advanced Datasheet	CAES reserves the right to make changes to any products and services described herein at any time without notice. The product is still in the development stage and the datasheet is subject to change . Specifications can be TBD and the part package and pinout are not final .
Preliminary Datasheet	CAES reserves the right to make changes to any products and services described herein at any time without notice. The product is in the characterization stage and prototypes are available.
Datasheet	Product is in production and any changes to the product and services described herein will follow a formal customer notification process for form, fit or function changes.

The following United States (U.S.) Department of Commerce statement shall be applicable if these commodities, technology, or software are exported from the U.S.: These commodities, technology, or software were exported from the United States in accordance with the Export Administration Regulations. Diversion contrary to U.S. law is prohibited.

Cobham Colorado Springs Inc. d/b/a Cobham Advanced Electronic Solutions (CAES) reserves the right to make changes to any products and services described herein at any time without notice. Consult an authorized sales representative to verify that the information in this data sheet is current before using this product. The company does not assume any responsibility or liability arising out of the application or use of any product or service described herein, except as expressly agreed to in writing; nor does the purchase, lease, or use of a product or service convey a license under any patent rights, copyrights, trademark rights, or any other of the intellectual rights of the company or of third parties.